Sheet 1 of 11

FORM PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Attorney Docket No.: NICHIA-00700

Serial No.:09/463643

Applicant: Shuji Nakamura, et al.

Filing Date: January 25, 2000

Group Art Unit:

(37 CFR § 1.98(b))

				U.S. PATENT DOCUMENTS			•
Examiner Initials		Serial / Patent Number	Issue Date	Applicant / Patentee	Class	Subclass '	Filing Date
Brows	AA	3566215	2/23/71	Heywang	317	235	7/31/68
	AB	3593191	7/13/71	Henker	331	94.5	9/24/69
	AC.	3655439	4/11/72	Seiter	117	212	6/16/69
	AD	3658585	4/25/72	Folkmann, et al.	117	201	2/26/70
	AE	3704427	11/28/72	Heywang	331	94.5	6/3/64
	AF	3705567	12/12/72	Emels	118	49	1/22/71
1,	AG	3737737	6/5/73	Heywang, et al.	317	234.R	10/6/71
	НА	3747559	7/24/73	Dietze	118	48	5/15/72
<u> </u>	AI	3793984	2/26/74	Kasper, et al.	118	48	11/13/72
	AJ	3819974	6/25/74	Stevenson, et al.	313	499	3/12/73
_	AK	3853974	12/10/74	Reuschel, et al.	264	81	2/21/73
	AL	3941647	3/2/76	Druminski	156	612	3/8/73
	AM	3948693	4/6/76	Weyrich, et al.	148	171	7/23/74
	AN	3963537	6/15/76	Kniepkamp, et al.	148	175	8/27/74
	AO	3965347	6/22/76	Heywang	250	211J	11/12/74
	AP	3974561	8/17/76	Schnoeller	29	611	5/30/74
	AQ	4020791	5/3/77	Reuschel, et al.	118	49.1	11/19/74
	AR	4062035	12/6/77	Winstel	357	17	1/28/77
1	AS	4098223	7/4/78	Ertl, et al.	118	48	11/4/76
1	AT	4102298	7/25/78	Dietze, et al.	118	5	6/10/76
ĺ	AU	4108539	8/22/78	Gort, et al.	350	201	11/18/76
-1	AV	4113381	9/12/78	Epstein	356	5	11/18/76
	AW	4133702	1/9/79	Krimmel	148	1.5	8/11/77
	AX	4140546	2/20/79	Krimmel	148	1.5	8/1 <i>7/77</i>
	AY	4154625	5/15/79	Golovchenko et al.	148	1.5	11/16/77
	AZ	4170018	10/2/79	Runge	357	17	3/30/78
	ВА	4261770	4/14/81	Splittgerber, et al.	148	171	3/13/80
- []	BB	4351695	9/28/82	Hicher, et al.	156	603	1/2/81
₩	ВС	4404265	9/13/83	Manasevit	428	689	4/7/78
#	BD	4410993	10/18/83	Zschauer	372	44	4/17/81
	BE	4423349	12/27/83	Nakajima, et al.	313	487	7/1/81
Ų	BF	4505765	3/19/85	Trommer	148	171	6/17/83
BM	BG	4521448	6/4/85	Sasaki	427	88	3/3/83

Examiner:

Date Considered: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Sheet 2 of 11 Attorney Docket No.: NICHIA-00700 FORM PTO-1449 U.S. Department of Commerce Serial No.:09/463643 Patent and Trademark Office (Modified) Applicant: Shuji Nakamura, et al. INFORMATION DISCHOOSERE STATEMENT BY APPLICANT Filing Date: January 25, 2000 Group Art Unit: (37 CFR § 1.98(b)) 2/16/83 ВН 4531142 7/23/85 Weyrich, et al. 357 17 ΒI 384 12/3/84 4568206 2/4/86 Imazaike 530 ВJ 4596998 6/24/86 Krimmel 357 17 7/19/84 ВK 7/8/86 Falckenberg, et al. 427 74 9/12/84 4599244 BL 9/11/84 4599245 427 7/8/86 Falckenberg, et al. 74 BM 4604637 8/5/86 Ruhle, et al. 357 17 3/1/83 BN 156 2/27/85 4615766 10/7/86 Jackson, et al. 662 во 4656636 4/7/87 Amann, et al. 372 50 12/23/85 BP 148 171 6/6/85 4661175 4/28/87 Kuphal, et al. BQ 4670093 6/2/87 156 649 4/21/86 Macrz, et al. BR 4682337 7/21/87 372 44 9/13/85 Amann 4683574 BS Heinen 372 44 9/12/85 7/28/87 BT 372 9/6/85 4722088 1/26/88 Wolf 44 BU 4740259 4/26/88 Heinen 156 234 9/15/86 ΒV 372 4742525 5/3/88 Heinen, et al. 44 9/6/85 BW 372 4744088 3/13/87 5/10/88 Heinen, et al. 50 BX 350 3/13/85 4746195 5/24/88 Auracher, et al. 320 BY 4763979 8/16/88 Heywang 350 96.20 9/23/86 ВZ 9/5/86 4768199 8/30/88 Heinen, et al. 372 36 CA 4/1/87 350 96.12 4792200 12/20/88 Amann, et al. СВ 372 1/30/87 4792959 12/20/88 Mueiler, et al. 46 CÇ 4818722 4/4/89 437 129 5/26/87 Heinen CD 4829188 5/9/89 250 483.1 10/1/87 Shinomiya, et al. CE 4835575 357 2/3/88 5/30/89 Plibal 30 CF 357 4841344 6/20/89 Heinen 17 12/7/87 CG 4845723 7/4/89 Heinen, et al. 372 38 2/22/88 CH 4855118 8/8/89 423 301 4/12/88 Ichinose, et al. CI 4859903 8/22/89 Minematu, et al. 313 487 3/2/88 CJ 357 7/5/88 4864369 9/5/89 Snyder, et al. 17 CK 350 4869568 9/26/89 Schimpe 96.12 9/29/88 CL 4890033 12/26/89 Ichinomiya, et al. 313 487 6/28/88

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Schellhorn, et al.

Huang, et al.

Manabe, et al.

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Sheet 3 of 11 FORM PTO-1449 (Modified) INFORMATION DESCRIPTION OF TRANSPORTED TO TRANSPORT OF TRANSPORT

U.S. Department of Commerce Patent and Trademark Office

Attorney Docket No.: NICHIA-00700

Serial No.:09/463643

Applicant: Shuji Nakamura, et al.

Filing Date: January 25, 2000

Group Art Unit:

(37 CFR § 1.9	8(ь))			rining Date: January 2	5, 2000	Group Art Omt.				
Bub	CR	4918497	4/17/90	Edmond		357	17	12/14/88		
1	cs	4929907	5/29/90	Berkel	·	330	252	3/8/89		
	CT	4944837	7/31/90	Nishikawa, et al.		156	646	2/28/89		
	CU	4945394	7/31/90	Palmour, et al.		357	34	10/26/87		
	CV	4946547	8/7/90	Palmour, et al.		156	643	10/13/89		
	CM	4947218	8/7/90	Edmond, et al.		357	13	11/3/87		
	сх	4959174	9/25/90	Nakajima, et al.		252	301.6R	3/16/89		
	CY	4960728	10/2/90	Schaake, et al.		437	82	10/11/88		
	CZ	4966862	10/30/90	Edmond		437	100	8/28/89		
	DA	4971739	11/20/90	Ichinose, et al.		264	61	4/12/89		
	DB	4977567	12/11/90	Hanke		372	45	10/11/89		
	DC	4982314	1/1/91	Miki		363	16	12/4/89		
	DD	4985742	1/15/91	Pankove		357	34	7/7/89		
	DE	4987576	1/22/91	Heinen		372	46	11/3/89		
	DF	4990466	2/5/91	Shieh, et al.		437	129	11/1/88		
	DG	4990990	2/5/91	Albrecht, et al.		357	30	3/23/88		
	DH	5005057	4/2/91	Izumiya, et al.		357	17	4/13/90		
	DI	5006908	4/9/91	Matsuoka, et al.		357	17	2/12/90		
	DJ	5008735	4/16/91	Edmond, et al.		357	· 74	12/7/89		
	DK	5008789	4/16/91	Arai, et al.		362	255	2/14/90		
	DL	5019746	5/28/91	Merg		313	512	12/4/89		
	DM	5023686	6/11/91	Helmut, et al.		357	30	6/15/90		
	DN	5027168	6/25/91	Edmond		357	17	8/28/89		
	DO	5034956	7/23/91	Gessner, et al.		372	45	11/2/89		
	DP	5041334	8/20/91	Nakajima, et al.		428	407	12/19/89		
	DQ	5042043	8/20/91	Hatano, et al.		372	45	4/13/90		
	DR	5045896	9/3/91	Ash, et al.		357	17	3/21/89		
	DS	5049779	9/17/91	Itsuki, et al.		313	486	4/28/89		
	DT	5061972	10/29/91	Edmond		357	13	9/13/90		
	טט	5065207	11/12/91	Heinen		357	30	2/5/91		
	DV	5077145	12/31/91	Shinomiya, et al.		428	691	12/21/90		
	D₩	5093576	3/3/92	Edmond, et al.		250	370.01	3/15/91		
	DX	5119540	6/9/92	Kong, et al.		29	25.01	7/24/90		
	DY	5120619	6/9/92	Nakajima, et al.		428	690	11/7/90		
	DZ	5122845	6/16/92	Manabe, et al.		357	17	2/26/90		
18MB	EA	5128955	7/7/92	Danielmeyer		372	94	8/18/88		
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT Attorney Docket No.: NICHIA-00700 Serial No.:09/463643 **FORM PTO-1449** U.S. Department of Commerce (Modified) Patent and Trademark Office Applicant: Shuji Nakamura, et al. Filing Date: January 25, 2000 Group Art Unit: (37 CFR § 1.98(b)) ЕВ 5146465 9/8/92 Khan, et al. 372 437 100 EC 10/13/92 Coleman 5155062

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		ED	5171370	12/15/92	Reithmaier, et al.	1	118	726	4/18/90
\vdash		EE	5182670	1/26/93	Khan, et al.	3	359	359	8/30/91
		EF	5184247	2/2/93	Schimpe	3	359	344	7/17/90
		EG	5185207	2/9/93	Furuoka, et al.	4	128	404	12/27/91
		EH	5200022	4/6/93	Kong, et al.	1	156	612	10/3/90
		EI	5202777	4/13/93	Sluzky, et al.	3	359	50	4/1/92
	T	EJ	5205905	4/27/93	Kotaki, et al.	1	156	662	5/30/91
		EK	5208878	5/4/93	Thulke	3	385	14	10/2/91
		EL	5210051	5/11/93	Carter, Jr.	4	137	107	6/5/91
		EM	5218216	6/8/93	Manabe, et al.	2	257	103	12/20/91
		EN	5229626	7/20/93	Ebitani, et al.	2	257	84	3/27/92
	1	EO	5233204	8/3/93	Fletcher, et al.	2	257	13	1/10/92
		EP	5239188	8/24/93	Takeuchi, et al.	2	257	76	11/4/92
		EQ	5247533	9/21/93	Okazaki, et al.	3	372	45	12/26/91
		ER	5250366	10/5/93	Nakajima, et al.	4	128	690	5/8/92
		ES	5252499	10/12/93	Rothschild	4	137	22	8/15/88
		ET	5252839	10/12/93	Fouquet	2	257	13	6/10/92
		EU	5260960	11/9/93	Amann, et al.	3	372	46	4/23/92
		EV	5264713	11/23/93	Palmour	7	257	77	6/14/91
		EW	5266503	11/30/93	Wang, et al.	4	437	24	10/2/91
	$\neg \vdash$	EX	5270554	12/14/93	Palmour	1	257	77	6/14/91
	\top	EY	5272108	12/21/93	Kozawa	4	437	127	2/26/92
		EZ	5278433	1/11/94	Manabe, et al.	2	257	103	8/7/92
	\top	FA	5281830	1/25/94	Kotaki, et al.		257	86	10/24/91
		FB	5290393	3/1/94	Nakamura	1	156	613	1/28/92
	\top	FC	5306662	4/26/94	Nakamura, et al.	4	437	107	11/2/92
		FD	5312560	5/17/94	Somatomo, et al.		252	301.4 S	3/18/93
	I	FE	5323022	6/21/94	Glass, et al.		257	77	9/10/92
		FF	5330791	7/19/94	Aihara, et al.		427	215	4/16/93
		FG	5334277	8/2/94	Nakamura ·		117	102	10/22/91
		FH	5336080	8/9/94	Sumitomo, et al.	- 4	428	407	12/17/92
		FI	5338944	8/16/94	Edmond, et al.		257	76	9/22/93
	T	FJ	5341390	8/23/94	Yamada, et al.		372	45	4/15/93
18	WB	FK	5343316	8/30/94	Morimoto, et al.		359	50	6/29/93
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Sheet 5 of 11 FORM PTO-1449 (Modified)

(37 CFR § 1.98(b))

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT U.S. Department of Commerce Patent and Trademark Office

Attorney Docket No.: NICHIA-00700

Serial No.:09/463643

Applicant: Shuji Nakamura, et al.

Filing Date: January 25, 2000

Group Art Unit:

Examiner:	Ela	Boson			Date Considered: 9	15/01	
BER	GÜ	5523589	6/4/96	Edmond, et al.	257	77	9/20/94
	GT	5523018	6/4/96	Okada, et al.	252	301.4 P	3/23/95
	GS	5514627	5/7/96	Lowery, et al.	437	209	1/24/94
	GR	5511084	4/23/96	Amann	372	20	1/17/95
	GQ	5506421	4/9/96	Palmour	257	77	11/24/92
	GP	5502316	3/26/96	Kish, et al.	257	94	10/12/95
	GO	5497012	3/5/96	Moll	257	183	6/15/94
	GN	5475241	12/12/95	Harrah, et al.	257	99	10/27/93
	GM	5468678	11/21/95	Nakamura, et al.	437	107	1/12/94
	GL	5467291	11/14/95	Fan, et al.	364	578	12/5/91
	GK	5465249	11/7/95	Cooper, Jr. et al.	365	149	11/26/91
	GJ	5459107	10/17/95	Palmour	437	238	6/5/92
	GI	5438198	8/1/95	Ebitani, et al.	250	330	5/3/94
	GH	5435938	7/25/95	Bando, et al.	252	301.4 S	3/10/94
	GG	5433888	7/18/95	Okada, et al.	252	301.4 R	9/20/93
	GF	5433533	7/18/95	Imazaike	384	488	12/20/93
	GE	5433169	7/18/95	Nakamura	117	102	4/6/94
_	GD	5417886	5/23/95	Tatciwa, et al.	252	301.4 R	9/20/93
	GC	5416342	5/16/95	Edmond, et al.	257	76	6/23/93
$\neg \uparrow \neg$	GB	5409859	4/25/95	Glass, et al.	437	187	4/22/94
	GA	5408120	4/18/95	Manabe, et al.	257	431	1/22/93
	FZ	5404282	4/4/95	Klinke, et al.	362	249	8/19/94
	FY	5403774	4/4/95	Shieh, et al.	437	129	11/6/92
-	FX	5394005	2/28/95	Brown, et al.	257	461	2/18/94
	FW	5393993	2/28/95	Edmond, et al.	257	77	12/13/93
	FV	5390210	2/14/95	Fouquet, et al.	372	92	11/22/93
	FU	5389571	2/14/95	Takeuchi, et al.	437	133	4/16/93
	FT	5382822	1/17/95	Stein	257	410	9/27/93
- -	FS	5381103	1/10/95	Edmond, et al.	324	753	10/13/92
	FR	5376580	12/27/94	Kish, et al.	437	127	3/19/93
	FQ	5376303	12/27/94	Royce, et al.	252	301.4 R	1/10/94
_	FP	5369289	11/29/94	Tamaki, et al.	257	99	10/30/92
	FO	5366834	11/22/94	Yoneda, et al.	430	23	5/5/93
-\	FN	5363390	11/8/94	Yang, et al.	372	22	11/22/93
DWY _	FM	5359345	10/25/94	Hunter	345	102	8/5/92
6WB	FL	5344791	9/6/94	Huang	437	126	8/14/92

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INFORMATION AUSCIL COMME STATEMENT BY APPLICANT U.S. Department of Commerce Patent and Trademark Office

Attorney Docket No.: NICHIA-00700 Serial No.:09/463643

Applicant: Shuji Nakamura, et al.

(37 CFR § 1.98(b))

FORM PTO-1449

(Modified)

Filing Date: January 25, 2000

Group Art Unit:

bno	GV	5539217	7/23/96	Edmond, et al.	257	77	8/9/93
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В	GW	5563422	10/8/96	Nakamura, et al.	257	13	4/28/94
1	GX	5578839	11/26/96	Nakamura, et al.	257	96	11/17/93
	GY	5583879	12/10/96	Yamazaki, et al.	372	45	4/19/95
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	нв	5592501	1/7/97	Edmond, et al.	372	45	9/20/94
	нс	5592578	1/7/97	Ruh	385	31	11/1/95
	HD	5596595	1/21/97	Tan, et al.	372	96	6/8/95
	HE	5604135	2/18/97	Edmond, et al.	437	22	8/12/94
	HE	5604763	2/18/97	Kato, et al.	372	45	4/19/95
	HG	5612260	3/18/97	Palmour	437	238	12/9/94
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\neg	HI	5616177	4/1/97	Yamada	117	102	2/22/95
	НJ	5620557	4/15/97	Manabe, et al.	438	507	6/26/95
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	HL	5625202	4/29/97	Chai	257	94	6/8/95
	нм	5627244	5/6/97	Sato	526	92	4/26/95
	HN	5629531	5/13/97	Palmour	257	77	12/9/94
	но	5631190	5/20/97	Negley	438	33	10/7/94
	НР	5635146	6/3/97	Singh, et al.	423	65	11/30/95
	HQ	5642375	6/24/97	King, et al.	372	97	10/26/95
	HR	5650641	7/22/97	Sassa, et al.	257	88	8/31/95
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\neg	нт	5652438	7/29/97	Sassa, et al.	257	94	7/19/95
	HO	5656832	8/12/97	Ohba, et al.	257	190	3/8/95
	HV	5659568	8/19/97	Wang, et al.	372	96	5/23/95
	HW	5661074	8/26/97	Tischler	438	32	5/24/95
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	IB	5684623	11/4/97	King, et al.	359	346	11/21/96
	IC	5686737	11/11/97	Allen	257	77	9/16/94
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Sheet 7 of 11 FORM PTO-1449 U.S. Department of Commerce ed) Patent and Trademark C INFORMATION DEPOSITES STATEMENT BY APPLICANT (Modified) Patent and Trademark Office Filing Date: January 25, 2000 (37 CFR § 1.98(b))

Attorney Docket No.: NICHIA-00700 Serial No.:09/463643 Applicant: Shuji Nakamura, et al.

Group Art Unit:

							
BAT) IF	5718760	2/17/98	Carter, et al.	117	84	2/5/96
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	IL	5729029	3/17/98	Rudaz	257	13	9/6/96
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	10	5734182	3/31/98	Nakamura, et al.	257	96	6/10/96
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